


PRODUCT APPROVAL SHEET



Product Type	XMD-SMD3225 Quartz Crystal
CREC's P/N	01.X.MD.120JMVCA008000000
Description	X'Tal XMD-SMD3225 8.000000MHz 20pF ±20ppm 300ohm
Customer Number	SHC002
Customer P/N	J40070014
Customer Name	-
Veision	B0

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Sign	杨静		杨静
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Assembly				
Test				
Web Site	www.chinacrec.com			



PRODUCT SPECIFICATION

XMD-SMD3225 Quartz Crystal

IATF 16949

AEC Q200



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1 Parts explanation

This part is a miniature AT cut stirp crystal units with SMD3225 miniature BASE. It is mainly used in mobile , wifi and Automotive, bluetooth and telecommunications application.

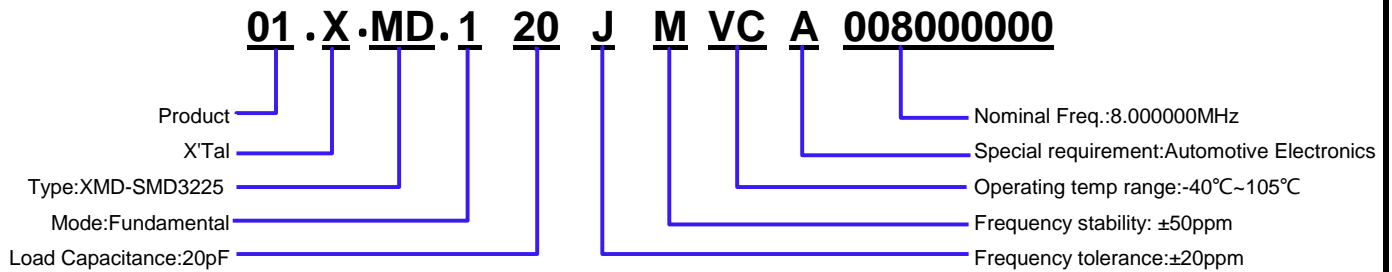
2 SCOPE

This specification only covers CREC's 01.X.MD.120JMVCA008000000

3 Reference Standard

- 3.1 MIL-STD-883H :Environmental tests' Mechanical tests.
- 3.2 MIL-STD-202 : Test Methods for Electronic and Electrical component part.
- 3.3 IEC 60068-2 :Environmental tests' Mechanical tests.
- 3.4 ANSI/EIA-481-C : 8mm through 200mm embossed carrier taping and 24mm punched
- 3.5 JEDEC J-STD-020C: Soldering
- 3.6 AEC-Q200: Reliability Test Item

4 Title Guide



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5 Performance

Electrical Performance. Electrical characteristics measured by S&A250B.

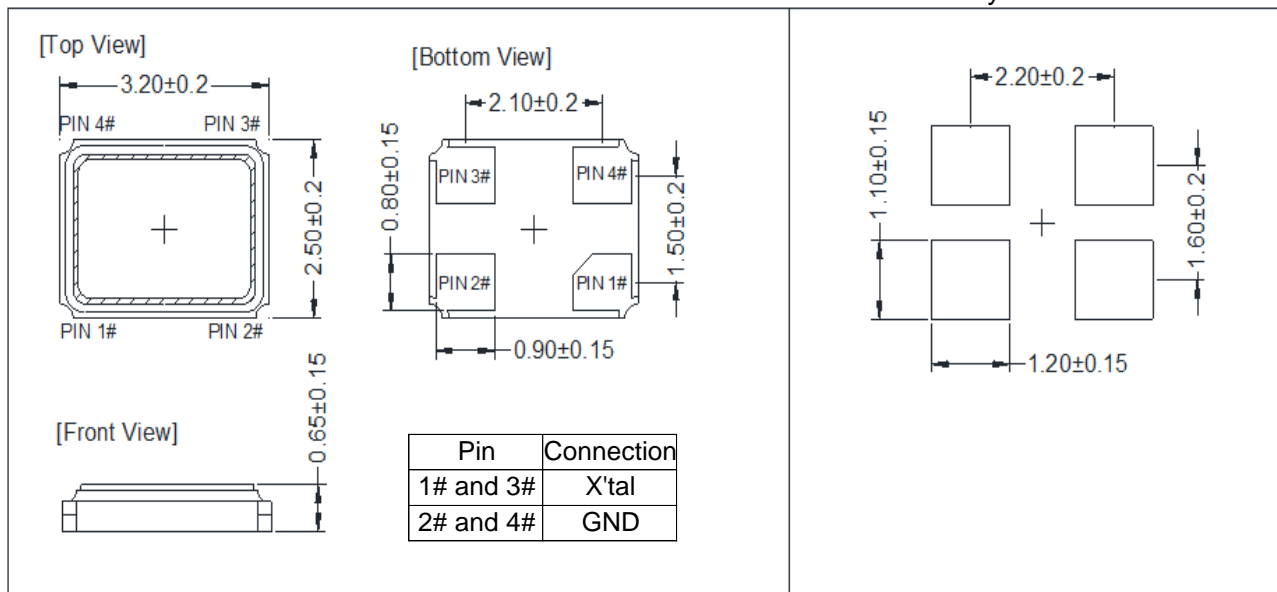
No.	Item	Symb.	Electrical Specification				Remark (Humidity: 40%~60%)
			Min.	Type	Max.	Unit	
1	Nominal Frequency	F0	8.000000			MHz	-
2	Mode of vibration	-	Fundamental			-	-
3	Frequency tolerance	$\Delta F/F_0$	-20	-	20	ppm	25°C±3°C
4	Operating Temperature Range	T _{OPR}	-40	-	105	°C	-
5	Frequency Stability	T _C	-50	-	50	ppm	Ref 25°C±3°C
6	Storage Temperature	T _{stg}	-55	-	125	°C	-
7	Load Capacitance	CL	-	20	-	pF	-
8	Equivalent Series Resistance	ESR	-	-	300	Ω	25°C±3°C
9	Drive Level	DL	-	-	100	μW	-
10	Insulation Resistance	IR	500	-	-	Mohm	@DC100V
11	Shunt Capacitance	C0	-	-	2	pF	25°C±3°C
12	Motional Capacitance	C1	-	-	-	fF	25°C±3°C
13	Spurious	SPDB	-	-	-3	dB	±5000ppm
14	Aging	Aging	-3	-	3	ppm	First Year
15	Reliability	-	AEC-Q200				

6 Figure

6.1 Product Dimensions and Solder Pad Layout Dimensions (Unit:mm)

Product Dimensions

Solder Pad Layout Dimensions



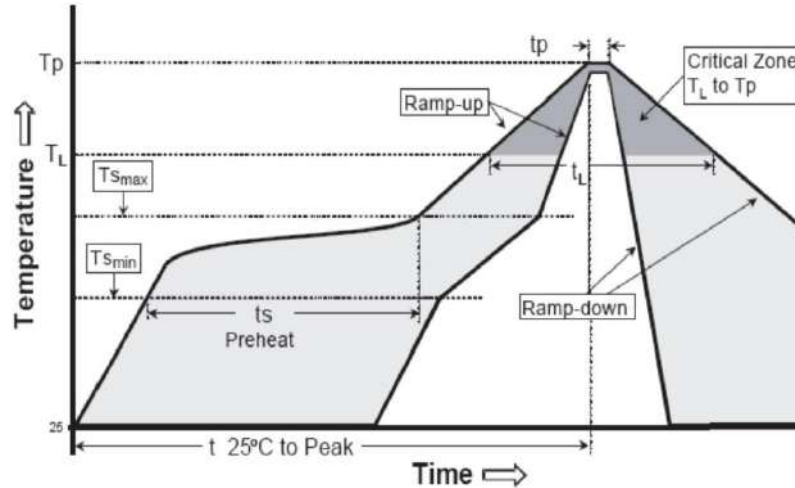
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6.2 Marking



No.	Item		E.G.	Remark
1	X.XXXX	Nominal Frequency (MHz) 6digit	8.0000	8.0000=8.000000MHz
2	CC	Load Capacitance (pF)	20	20=20pF
3	CREC	LOGO	CREC	-
4	Y	Year: Last 1 Digit	2	2022 Year
5	WW	Week Code 2 Digit	29	29th Week

7 IR Reflow Profile



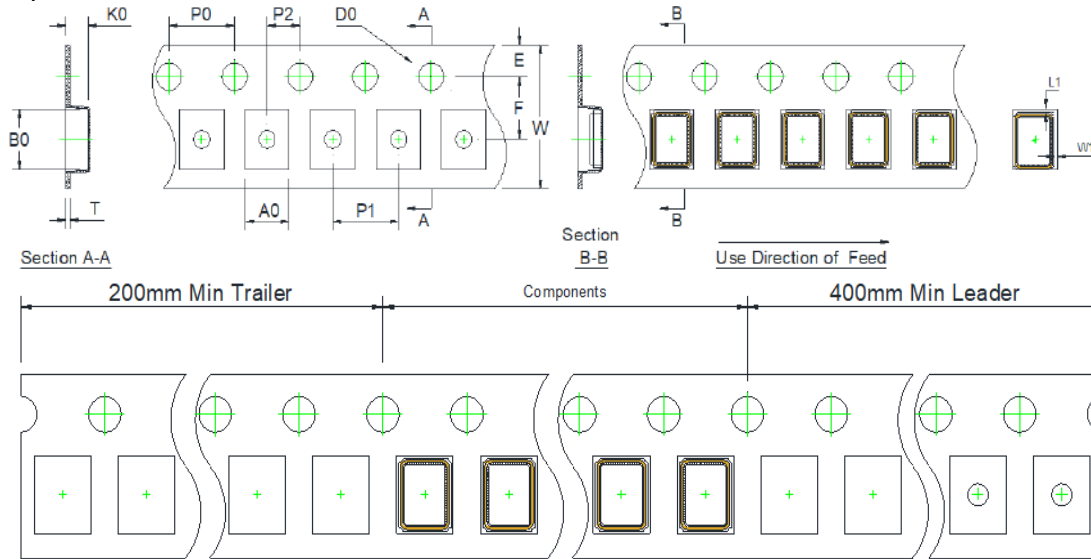
Remark: Reference JEDEC J-STD-020C

Profiles Feature	Pb-Free Assembly
Average Ramp-up Rate (Ts max to Tp)	3°C/second max.
Preheat	
■ Temperature Min (Ts min)	125°C
■ Temperature Max (Ts max)	200°C
■ Time (ts min to ts max)	60~180 seconds
Time maintained above	
■ Temperature (TL)	217°C
■ Time (tL)	60~150 seconds
Peak/Classification Temperature (Tp)	260°C
Time within 5°C of actual Peak	20~40 seconds
Temperature (tp)	
Ramp-down rate	6°C/second Max
Time 25°C to Peak Temperature	8 minutes Max
Suggest reflow times	3 times

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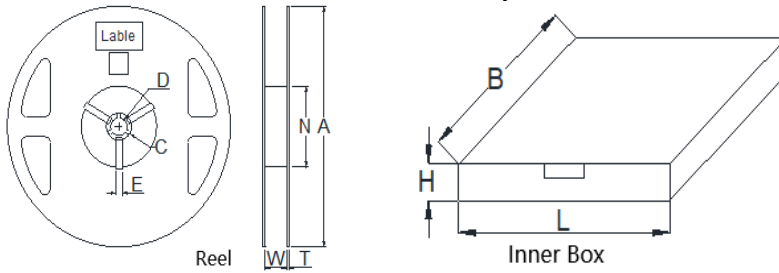
8 Packing specification

8.1 Tape Dimensions



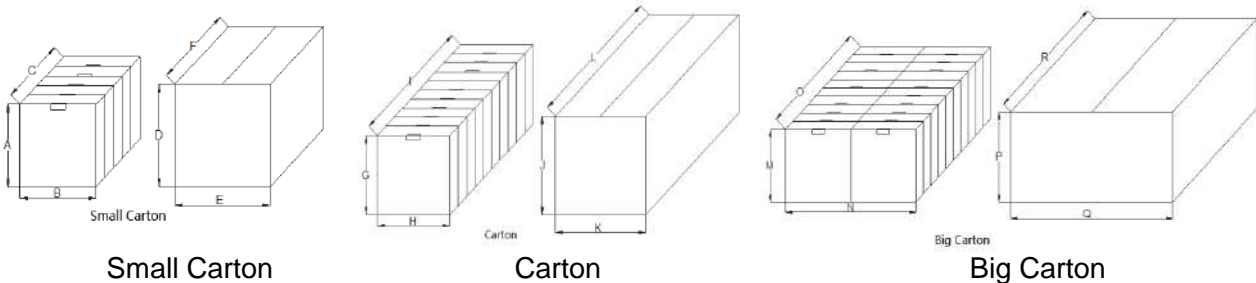
ITEM	W	P1	E	F	D0	P0	P2	A0	B0	K0	T	L1	W1
Spec(mm)	8.00	4.00	1.75	3.50	1.55	4.00	2.00	2.70	3.40	1.40	0.25	0.20	0.20
Tol.(mm)	±0.30	±0.10	±0.22	±0.10	±0.05	±0.10	±0.10	±0.10	±0.10	±0.10	±0.05	±0.05	±0.05

8.2 Reel and Inner Box Dimensions and Q'ty



Item	Reel							Inner Box		
	A	W	N	C	D	E	T	L	B	H
SPEC(mm)	178	9.3	60.0	20.0	13.0	2.3	1.4	180	180	30
Tol.(mm)	±2.0	±0.5	±0.5	±1.0	±0.5	±0.5	±0.2	-	-	-
Q'ty (pcs)	3K/Reel Max							6K/Box Max		

8.3 Carton Dimensions and Q'ty



Item	Small Carton						Carton						Big Carton					
	A	B	C	D	E	F	G	H	I	J	K	L	M	N	O	P	Q	R
SPEC(mm)	180	180	150	230	230	230	180	180	300	230	230	350	180	360	300	230	350	410
Q'ty (pcs)	30K/Carton Max						60K/Carton Max						120K/Carton Max					

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9 Reliability Test Item

No.	Item	Test Condition	Reference
1	High Temperature Storage	Temperature: 125°C ± 5°C Time 1000 hours	MIL-STD-202 Method 108
2	Temperature Cycle	1000 cycles (-40°C to 125°C),30min max dwell time at peak temperature. 1 min. maximum transition time	JESD22 Method JA-104
3	Biased Humidity	Temperature: 85°C ± 2°C Relative Humidity: 85% Time: 1000 hours.	MIL-STD-202 Method 103
4	Operational Life	Temperature: 125°C Time:1000 hours	MIL-STD-883H Method 1008.2
5	Mechanical Shock	100g, half-sine, Duration:6ms, Each direction for 3 times in X,Y,Z	MIL-STD-202 Method 213, condition C
6	Vibration	Frequency: 10 to 2000 Hz, full wave Amplitude: 1.52 mm (Peak to Peak) Direction: X, Y,Z Duration: 20 Minutes 12 cycles each of 3 orientation	MIL-STD-202 METHOD 204
7	Resistance to Soldering Heat	Pre-Heating:125°C 60~120 Seconds, Solder temperature: 260± 5°C, Time: 10±5 sec	MIL-STD-202 Method 210B
8	Solderability	4Hrs dry heat 155°C Dipping 235±5°C 5±0.5 sec	J-STD-002
9	Board Flex	60 sec minimum holding time, Deflection min :2mm	AEC Q200-005
10	Terminal Strength	Force : 1.8Kg Test duration : 60+1 sec	AEC Q200-006

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10 Product handling and control procedure

10.1 Precautions for storage

Storage of crystal units under higher temperature or high humidity for a long term may affects frequency stability or solderability. Please store the crystal units under the normal temperature and humidity without exposing to direct sunlight and dew condensation, and avoid the storage of crystal units for more than 6 months, and mount them as soon as possible after unpacking.

Item		Electrical Specification			
		Min.	Type	Max.	Unit
Storage peiod	After customer assembly	15		-	Year
	Crystal unused	-		2	Year

10.2 Mounting of SMD Type products

When using an automatic loading machine, please test and confirm to cause no damage to the crystal units before mounting. Bending the circuit board in the process of cleaving boards after mounting and soldering crystal units may cause peeling off the soldering or package cracks by mechanical stress.

10.3 Ultrasonic cleaning

General cleaning solutions or ultrasonic cleaning method may be used to clean CREC's products. However, under certain circumstances, ultrasonic cleaning machine could generate resonance at the oscillaton frequency of our products and thus deteriorate the electrical characteristics in devices, and even damage the overall structure of devices. Therefore, verification test is recommended before cleaning.

10.4 Ultrasonic welding

Avoid mounting and processing by Ultrasonic welding this method has a possibility of an excessive vibration spreading inside the crystal products and becoming the cause of characteristic deterioration and not oscillating. If Ultrasonic welding is being used in process, please notify us in advance to verify it.

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